

What is claimed is:

1. A semiconductor integrated circuit device comprising:
 first and second circuit blocks;
 an interface checker to monitor whether waveforms of signals between the first and second circuit blocks conform to an interface specification of a design data of the first circuit block; and
 an external output pin to output a result of a monitoring of the interface checker to an external of the semiconductor integrated circuit device.
2. The semiconductor integrated circuit device according to claim 1,
 wherein the external output pin outputs a first value indicating a conformity of the waveforms to the interface specification or a second value indicating a nonconformity of the waveforms to the interface specification.
3. The semiconductor integrated circuit device according to claim 1,
 wherein the interface specification describes timing information in synchronization with a clock signal.
4. A design method of a semiconductor integrated circuit device comprising;
 providing a design data and an interface specification of the design data;
 generating a synthesizable interface checker in accordance with the interface specification;
 producing a semiconductor integrated circuit including a first logic circuit according to the design data and the interface checker according to the synthesizable interface checker; and
 monitoring whether waveforms of signals between the first circuit block and another circuit block conform to the interface specification of the design data.
5. The design method of the semiconductor integrated circuit device according to claim 4, further comprising;
 outputting a first value indicating a conformity of the waveforms to the interface specification or a second value indicating a nonconformity of the waveforms to the interface specification to an external of the semiconductor integrated circuit device.